

Search Notes**Application/Control No.**

10/690,463

Examiner

TAN N. TRAN

Applicant(s)/Patent under Reexamination

CHENG, JYH-NAN

Art Unit

2826

SEARCHED

Class	Subclass	Date	Examiner
257	173	02/05	TT
	340		
	341		
	342		
	343		
	344		
	355		
	365		
↓	208	↓	✓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	02/05	TT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner